AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions and listings of claims in the application:

Listing of claims:

1.   (original) A method of characterizing a device under test, the method comprising:

injecting a signal into the device under test;

measuring the response to the injected signal to determine the impedance of the device under test in the frequency domain;

converting the impedance of the device under test to a time domain; and

calculating the voltage noise of the device under test based on the impedance in the time domain.

2.   (original) The method of claim 1 in which the step of measuring the response includes constructing an s-parameter matrix and calculating the real and imaginary portions of the impedance of the device under test as a function of frequency based on the s-parameter matrix.

3.   (original) The method of claim 2 in which the step of construction the s-parameter matrix includes establishing calibration data, generating an uncorrected s-parameter matrix based on the measured impedance of the device under test, and applying the calibration data to the uncorrected s-parameter matrix to produce a corrected s-parameter matrix.

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